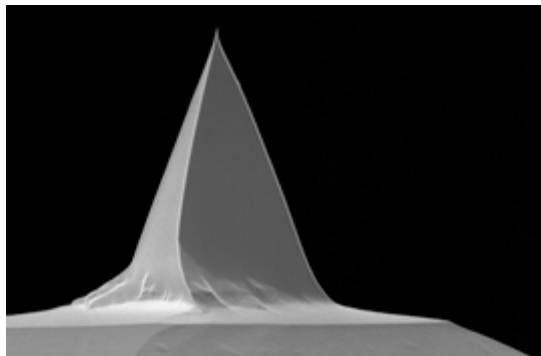


ANSCM-PT

ANSCM-PT probes are force modulation probes designed for Electronic Force Microscopy applications. These probes are coated on the reflex and tip sides with a thin layer of Pt-Ir, which allows for high resolution imaging.

Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height (μm):** 14-16
- **Aspect ratio:** 1.5-3.0
- **ROC (nm) :** 30
- **Coating:** Pt/Ir, 25 nm \pm 5



ANSCM-PT

On click zoom images

Download Spec

Cantilever Specifications

Material: Silicon

Shape :Rectangular

Reflex Pt/Ir, 25 nm
coating \pm 5

Parameter	Nominal	Min	Max
k (N/m)	3.0	1.0	5.0
f (kHz)	60.0	50.0	70.0
Length (μm)	225.0	215.0	240.0
Width (μm)	45.0	40.0	50.0
Thickness (μm)	2.50	2.00	3.00